

Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2856

SEARCHED

Class	Subclass	Date	Examiner
73	504.02	5/19/2005	HK
73	504.04	5/19/2005	HK
73	504.12	5/19/2005	HK
73	504.14	5/19/2005	HK
73	504.15	5/19/2005	HK
73	514.32	5/19/2005	HK
73	514.16	5/19/2005	HK
73	514.29	5/19/2005	HK
73	514.36	5/19/2005	HK
73	514.37	5/19/2005	HK
73	514.38	5/19/2005	HK
73	514.23	5/19/2005	HK
73	514.24	5/19/2005	HK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner